

<b>Notice of References Cited</b>	Application/Control No. 10/613,440	Applicant(s)/Patent Under Reexamination HEIDORN ET AL.	
	Examiner Joselynn Y. Sliteris	Art Unit 3616	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,765,869	06-1998	Huber, John F.	280/733
	B	US-6,126,194	10-2000	Yaniv et al.	280/733
	C	US-6,217,063	04-2001	Takeuchi, Hiroyuki	280/733
	D	US-6,648,369	11-2003	Mishima et al.	280/733
	E	US-5,393,091	02-1995	Tanaka et al.	280/733
	F	US-6,698,790	03-2004	Iseki et al.	280/733
	G	US-5,474,326	12-1995	Cho, Sung H.	280/733
	H	US-5,390,953	02-1995	Tanaka et al.	280/733
	I	US-5,385,367	01-1995	Tanaka et al.	280/733
	J	US-5,354,096	10-1994	Tanaka et al.	280/733
	K	US-5,303,953	04-1994	Kamiyama et al.	280/733
	L	US-6,142,511	11-2000	Lewis, Donald J.	280/733
	M	US-RE37,280	07-2001	Tanaka et al.	280/733

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.